

Docket No.: 57454-970

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Hideto HIDAKA

Serial No.: 10/644,750

Filed: August 21, 2003

: Customer Number: 20277

: Confirmation Number: 7630

: Group Art Unit: 2818

: Examiner: Not yet assigned

For: MIS SEMICONDUCTOR DEVICE HAVING IMPROVED GATE INSULATING FILM
RELIABILITY

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT


Mail Stop Issue Fee
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Further to the Information Disclosure Statement filed on August 21, 2003 in the captioned application, it is noted that one reference in the previously filed Information Disclosure Statement was inadvertently identified incorrectly on the corresponding PTO-1449 form. However, the correct reference was provided along with the IDS in the parent application Serial No. 09/813,796. Enclosed herewith is a revised PTO-1449 form which correctly identifies the reference in issue, as well as a marked-up copy of the original PTO-1449 form showing the error. It would be appreciated if the Examiner would initial the revised PTO-1449 form and return it to the Applicant and enter the revised PTO-1449 form into the file at the USPTO, so that all prior art references are properly identified on any patent issuing from this application.

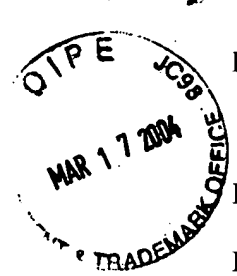
Respectfully submitted,

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WDC99 893975-1.057454.0970



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SHEET 1 OF 1

INFORMATION DISCLOSURE CITATION IN AN APPLICATION

(PTO-1449)


 ATTY. DOCKET NO.
57454-970

 SERIAL NO.
Divisional of Appln. Serial
No. 09/813,796

 APPLICANT
Hideto HIDAKA

 FILING DATE
August 21, 2003

 GROUP
Not yet assigned

U.S. PATENT DOCUMENTS

| EXAMINER'S INITIALS | CITE NO. | Document Number Number-Kind Code ² (if known) | Publication Date MM-DD-YYYY | Name of Patentee or Applicant of Cited Document | Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear |
|---------------------|----------|---|--------------------------------|---|---|
| | | US 6,414,889 | 07/2002 | Chen et al. | |
| | | US 6,107,134 | 08/2000 | Lu et al. | |
| | | US 5,956,279 | 09/1999 | Mo et al. | |
| | | US 5,694,364 | 12/1997 | Morishita et al. | |
| | | US 5,379,260 | 01/1995 | McClure | |
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FOREIGN PATENT DOCUMENTS

| EXAMINER'S INITIALS | CITE NO. | Foreign Patent Document Country Codes - Number - Kind Codes (if known) | Publication Date MM-DD-YYYY | Name of Patentee or Applicant of Cited Document | Pages, Columns, Lines Where Relevant Figures Appear | Translation | |
|---------------------|----------|---|--------------------------------|---|---|-------------|----|
| | | | | | | Yes | No |
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OTHER ART (including Author, Title, Date, Pertinent Pages, Etc.)

| EXAMINER'S INITIALS | CITE NO. | Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published. |
|---------------------|----------|---|
| | | "A Precise On-Chip Voltage Generator for a Gigascale DRAM with a Negative Word-Line Scheme", by Tanaka et al., IEEE Journal of Solid-State Circuits, Vol. 34, No. 8, 8/1999, pp. 1084-1090. |
| | | "Ultra LSI Memory" by Kiyoo Ito, Advanced Electronics Series, November 5, 1994, published by Baffukan, pp. 351-371. |
| | | "An Experimental 256-Mb DRAM with Boosted Sense-Ground Scheme", by Asakura et al., IEEE Journal of Solid-State Circuits, Vol. 29, No. 11, 11/1994, pp. 1303-1309. |
| EXAMINER | | DATE CONSIDERED |

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered.
 1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.